

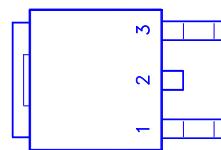
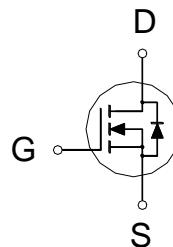
NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P1825HDB

TO-252

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
250V	230mΩ	18A


 1: GATE
 2: DRAIN
 3: SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	250	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ C$	I_D	18	A
	$T_C = 100^\circ C$		11	
Pulsed Drain Current ¹		I_{DM}	51	A
Avalanche Current		I_{AS}	9	
Avalanche Energy	$L = 1mH$	E_{AS}	40	mJ
Power Dissipation	$T_C = 25^\circ C$	P_D	74	W
	$T_C = 100^\circ C$		29	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W
Junction-to-Case	$R_{\theta JC}$		1.7	

¹Pulse width limited by maximum junction temperature.
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	250			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	2	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 250V, V_{GS} = 0V$			1	μA
		$V_{DS} = 200V, V_{GS} = 0V, T_J = 125^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 9A$		210	286	$m\Omega$
		$V_{GS} = 10V, I_D = 9A$		193	230	

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Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 9A$		21		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		788		pF
Output Capacitance	C_{oss}			115		
Reverse Transfer Capacitance	C_{rss}			14		
Total Gate Charge ²	Q_g			24		
Gate-Source Charge ²	Q_{gs}	$V_{GS} = 10V, V_{DS} = 200V$ $I_D = 18A$		3.3		nC
Gate-Drain Charge ²	Q_{gd}			8.4		
Turn-On Delay Time ²	$t_{d(on)}$			14		
Rise Time ²	t_r			101		
Turn-Off Delay Time ²	$t_{d(off)}$	$V_{DS} = 125V$, $I_D \approx 18A, V_{GS} = 10V, R_{GEN} = 6\Omega$		104		nS
Fall Time ²	t_f			79		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				18	A
Forward Voltage ¹	V_{SD}	$I_F = 18A, V_{GS} = 0V$			1	V
Diode Reverse Recovery Time	t_{rr}	$I_F = 18A, dI/dt = 100A/\mu s$		158		nS
Diode Reverse Recovery Charge	Q_{rr}			0.98		uC

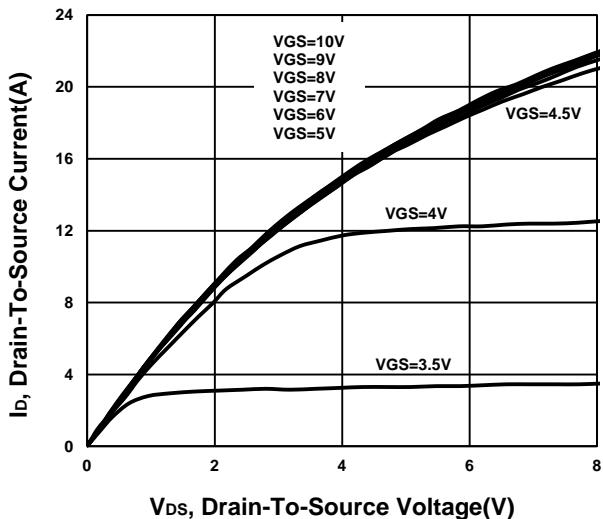
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

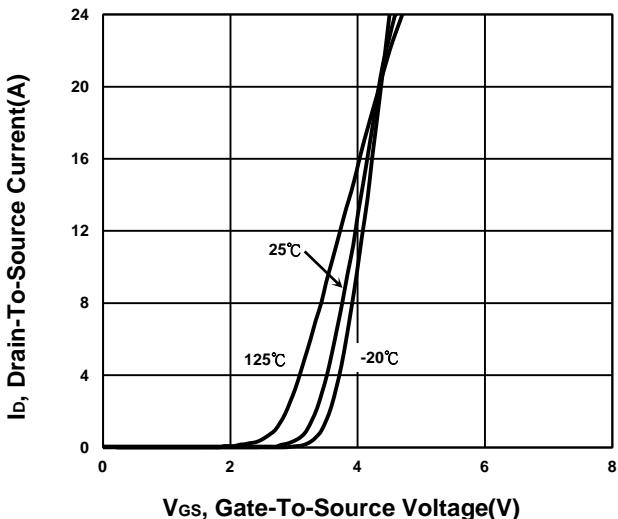
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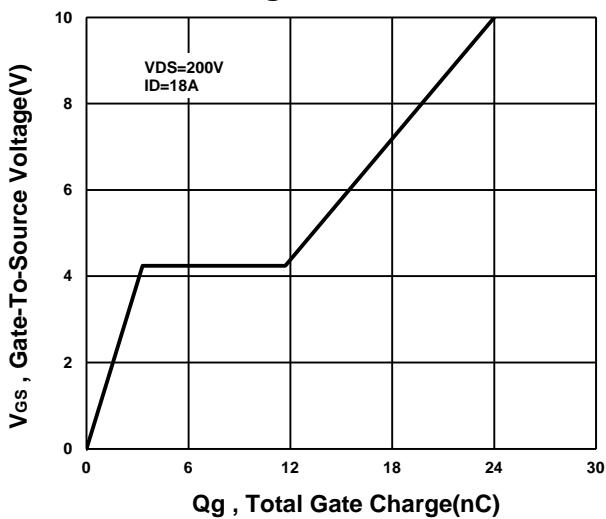
Output Characteristics



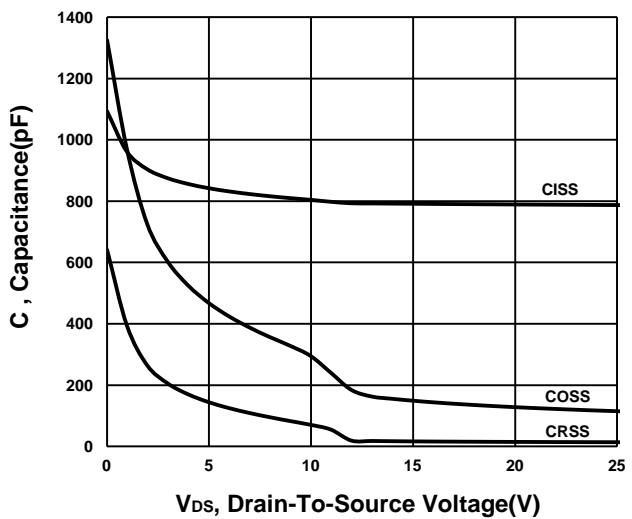
Transfer Characteristics



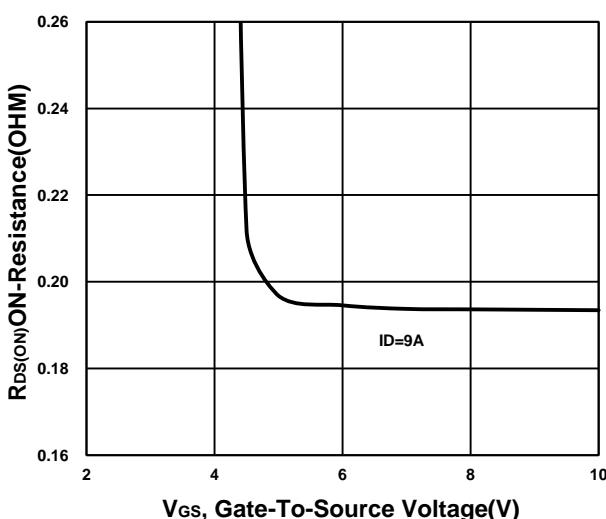
Gate charge Characteristics



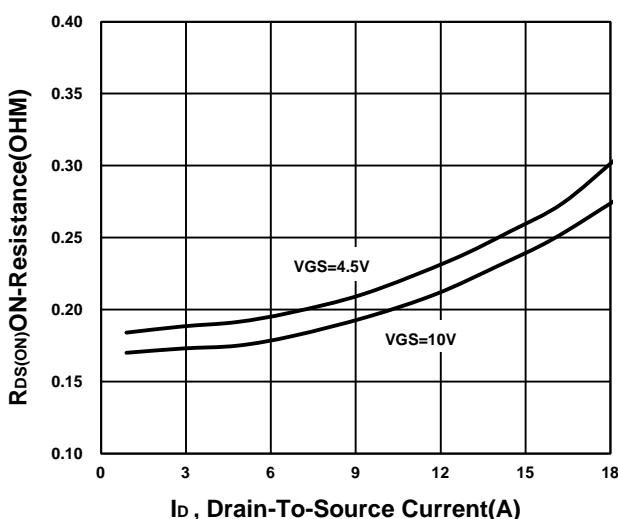
Capacitance Characteristic



On-Resistance VS Gate-to-Source



On-Resistance VS Drain Current



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